Sear	ch i	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/647,433	MIMURA ET AL.	
Examiner	Art Unit	
Binh X. Tran	1765	

SEARCHED			
Class	Subclass	Date	Examiner
438	711	4/12/2006	ВТ
438	719	4/12/2006	вт
438	728	4/12/2006	ВТ
438	729	4/12/2006	вт

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	711	4/12/2006	вт
438	719	4/12/2006	вт
438	728	4/12/2006	вт
438.	/729	4/12/2006	ВТ

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Updated keywords search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	4/12/2006	ВТ